

OCT 25 2007

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Jian Zhou; Hua Chu

Assignee: Nanometrics Incorporated

Title: Method for Automatically De-Skewing of Multiple Layer Wafer for Improved Pattern Recognition

Serial No.: 09/974,721 Filing Date: October 9, 2001

Examiner: Colin M. Larose Group Art Unit: 1765

Docket No.: NAN050 US Confirmation No.: 7841

Saratoga, California
October 25, 2007

Mail Stop RCE
Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE TO OFFICE ACTION

Dear Sir:

This Response to Office Action is responsive to the July 25, 2007, final Office Action, which has a statutorily shortened period for response that ends October 25, 2007. A Request for Continued Examination is attached hereto. The Commissioner is hereby authorized by the undersigned to debit any additional necessary fees from deposit account 50-2263. Please enter the following amendments before taking action on the merits of the above-referenced application.

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